

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L3	490	(difference contrast disagreement discrepancy disparateness disparity dissimilarity distinction distinctiveness distinctness diverseness diversity unlikeness deviance divergence change modification variation conflict discord discordance dissension dissent dissidence disunity friction strife variability variance incompatibility incongruity incongruousness disproportion) with (test\$3 near4 fixture)	US-PGPUB; USPAT; IBM_TDB	OR	ON	2007/07/11 11:08
L4	355	test\$3 with hardware with (calibrat\$3 or transformat\$3)	US-PGPUB; USPAT; IBM_TDB	OR	ON	2007/07/11 11:02
L5	8	L4 and ((two near3 different near3 fixture) ((plurality or many or multiple) with fixture) ((reference or product\$3) near7 fixture))	US-PGPUB; USPAT; IBM_TDB	OR	ON	2007/07/11 11:02
L7	309	test\$3 with hardware with calibrat\$3	US-PGPUB; USPAT; IBM_TDB	OR	ON	2007/07/11 11:02
L8	309	L7 and (@pd<"200040601" or @ad<"200040601" or @prad<"200040601" or @rlad<"200040601")	US-PGPUB; USPAT; IBM_TDB	OR	ON	2007/07/11 11:02
L9	391	L3 and ((measur\$3 gaug\$3 calculat\$3 comput\$7 figur\$3 estimat\$3 judg\$3 tall\$3 test\$3 examin\$5 inspect\$3 check\$3 observ\$3 analyz\$3 investigat\$3 diagno\$5) with (DUT device or circuit chip memory))	US-PGPUB; USPAT; IBM_TDB	OR	ON	2007/07/11 11:02
L10	2	L9 and ((test\$3 or interface) with hardware with calibrat\$3)	US-PGPUB; USPAT; IBM_TDB	OR	ON	2007/07/11 11:02
L11	2	L7 and L3	US-PGPUB; USPAT; IBM_TDB	OR	ON	2007/07/11 11:02
L12	283	L8 and ((measur\$3 gaug\$3 calculat\$3 comput\$7 figur\$3 estimat\$3 judg\$3 tall\$3 test\$3 examin\$5 inspect\$3 check\$3 observ\$3 analyz\$3 investigat\$3 diagno\$5) with (DUT device or circuit chip memory))	US-PGPUB; USPAT; IBM_TDB	OR	ON	2007/07/11 11:02

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L14	2	L8 and L3	US-PGPUB; USPAT; IBM_TDB	OR	ON	2007/07/11 11:02
L15	2	L8 and ((measur\$3 gaug\$3 calculat\$3 comput\$7 figur\$3 estimat\$3 judg\$3 tall\$3 test\$3 examin\$5 inspect\$3 check\$3 observ\$3 analyz\$3 investigat\$3 diagno\$5) with ((DUT device or circuit chip memory) with (plurality or many or different) with (test\$3 near7 fixture)))	US-PGPUB; USPAT; IBM_TDB	OR	ON	2007/07/11 11:02
L99	4020	L84 and ((measur\$3 gaug\$3 calculat\$3 comput\$7 figur\$3 estimat\$3 judg\$3 tall\$3 test\$3 examin\$5 inspect\$3 check\$3 observ\$3 analyz\$3 investigat\$3 diagno\$5) with (DUT device or circuit chip unit))	US-PGPUB; USPAT; IBM_TDB	OR	ON	2007/07/11 11:02
L100	11	L99 and ((difference contrast disagreement discrepancy disparateness disparity dissimilarity distinction distinctiveness distinctness diverseness diversity unlikeness deviance divergence change modification variation conflict discord discordance dissension dissent dissidence disunity friction strife variability variance incompatibility incongruity incongruousness disproportion compar\$3) with fixture\$1)	US-PGPUB; USPAT; IBM_TDB	OR	ON	2007/07/11 11:02
L114	224	(compar\$4 with test\$3 near4 fixture)	US-PGPUB; USPAT; IBM_TDB	OR	ON	2007/07/11 11:02
L115	17	L114 and "714"/\$.ccls.	US-PGPUB; USPAT; IBM_TDB	OR	ON	2007/07/11 11:02
L116	17	L115 and (@pd<"200040601" or @ad<"200040601" or @prad<"200040601" or @rlad<"200040601")	US-PGPUB; USPAT; IBM_TDB	OR	ON	2007/07/11 11:02
L117	15	calibrat\$3 near3 array with fixture	US-PGPUB; USPAT; IBM_TDB	OR	ON	2007/07/11 11:02
L121	66	calibrat\$3 with (plurality multiple) near4 fixture	US-PGPUB; USPAT; IBM_TDB	OR	ON	2007/07/11 11:02

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L122	34	L121 and (test\$3 diagnos\$5).clm.	US-PGPUB; USPAT; IBM_TDB	OR	ON	2007/07/11 11:02
L123	110	L3 and (adjust\$5 with (DUT device circuit))	US-PGPUB; USPAT; IBM_TDB	OR	ON	2007/07/11 11:15
L126	263	L3 and ((adjust\$5 adapt\$5 condition\$4 accommodat\$3 modif\$6) with (DUT device circuit))	US-PGPUB; USPAT; IBM_TDB	OR	ON	2007/07/11 11:17
L127	27	L126 and ((adjust\$5 adapt\$5 condition\$4 accommodat\$3 modif\$6) with calibrat\$3)	US-PGPUB; USPAT; IBM_TDB	OR	ON	2007/07/11 11:18